

CHILINK P-Channel Enhancement Mode Power MOSFET

Description

The LX30P30N combines advanced trench technology to provide excellent $R_{DS(ON)}$, it is tailored to minimize conduction loss, and provide superior switching performance.

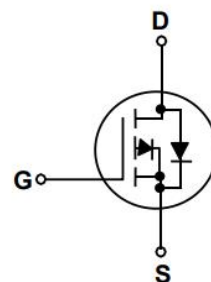
Features

- $V_{DS} = -30V$, $I_D = -30A$
 $R_{DS(ON)typ.} = 10.5m\Omega @ V_{GS} = -10V$
 $R_{DS(ON)typ.} = 15m\Omega @ V_{GS} = -4.5V$
- Fast Switching
- High Power and Current Handling Capability
- Termination is Lead-Free and RoHS Compliant

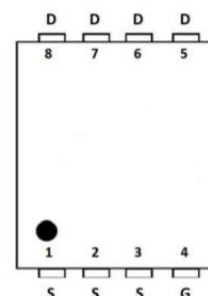


Applications

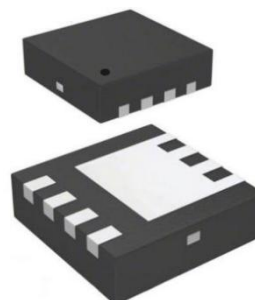
- PWM Applications
- Load Switch
- Power Management



Schematic Diagram



Pin Assignment



PDFN3*3 Package

Maximum Ratings

($T_A = 25^\circ C$ unless otherwise noted)

PARAMETER	SYMBOL	MAX	UNIT
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	$I_D (T_C = 25^\circ C)$	-30	A
	$I_D (T_C = 100^\circ C)$	-20	A
Pulsed Drain Current ^B	I_{DM}	-120	A
Maximum Power Dissipation ^A	P_D	16	W
Single Pulse Avalanche Energy	E_{AS}	180	mJ
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ C$

Thermal Characteristic

Thermal Resistance, Junction to Case	$R_{\theta JC}$	6.25	$^{\circ}\text{C/W}$
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Electrical Characteristics

($T_A=25^{\circ}\text{C}$ unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = -250\mu A$	-30			V
Gate-Threshold Voltage	$V_{th(GS)}$	$V_{DS} = V_{GS}, I_D = -250\mu A$	-1	-1.5	-2	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 12V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -30V, V_{GS} = 0V$			-1	μA
Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS} = -10V, I_D = -6A$		10.5	14	m Ω
		$V_{GS} = -4.5V, I_D = -5A$		15	19	m Ω

Dynamic Characteristics

Input Capacitance	C_{iss}	$V_{DS} = -15V, V_{GS} = 0V, F = 1MHz$		1582		pF
Output Capacitance	C_{oss}			198		
Reverse Transfer Capacitance	C_{rss}			173		

Switching Capacitance

Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -15V, R_L = 3\Omega, V_{GS} = -10V, R_{GEN} = 3\Omega$		13		ns
Turn-On Rise Time	t_r			8.5		ns
Turn-Off Delay Time	$t_{d(off)}$			26		ns
Turn-Off Fall Time	t_f			12		ns
Total Gate Charge	Q_g	$V_{DS} = -15V, I_D = -15A, V_{GS} = -10V$		29		nC
Gate-Source Charge	Q_{gs}			5		nC
Gate-Drain Charge	Q_{gd}			8		nC

Drain-Source Diode Characteristics

Diode Forward Voltage	V_{SD}	$V_{GS} = 0V, I_D = -10A$			-1.2	V
Diode Forward Current	I_S				-30	A

Notes:

- The Power dissipation P_D is based on $T_{J(MAX)}=150^{\circ}\text{C}$, using $\leq 10s$ junction-to-ambient thermal resistance.
- Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}=150^{\circ}\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^{\circ}\text{C}$.
- The Static characteristics in Figures are obtained using $<300\mu s$ pulses, duty cycle 2% max.
- E_{AS} condition: $T_J=25^{\circ}\text{C}$, $V_{DD}=-25V$, $V_{GS}=-10V$, $L=0.5mH$.

Typical Electrical and Thermal Characteristics

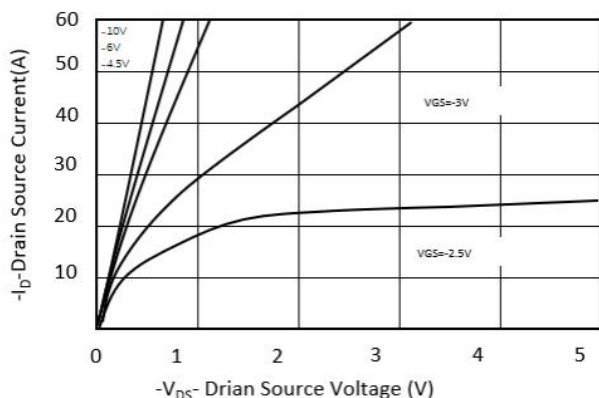


Figure 1. On-Region Characteristics

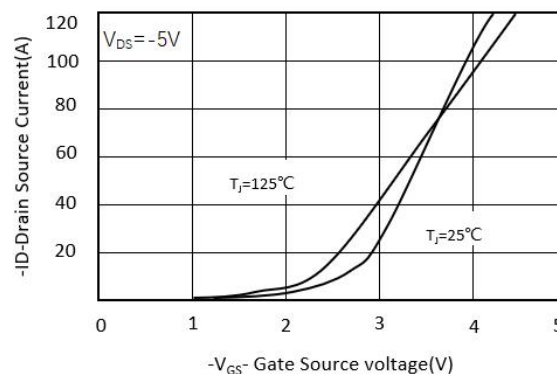


Figure 2. Transfer Characteristics

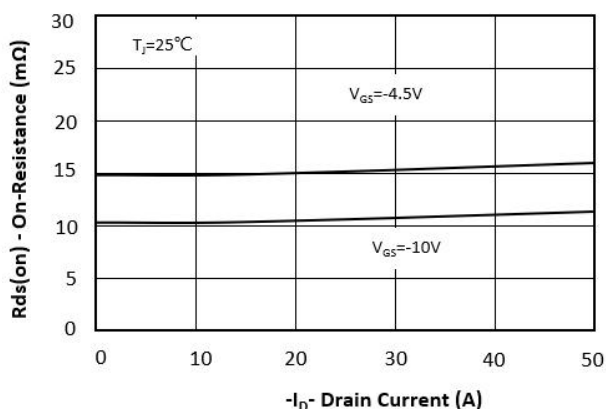


Figure 3. On-Resistance vs. Drain Current

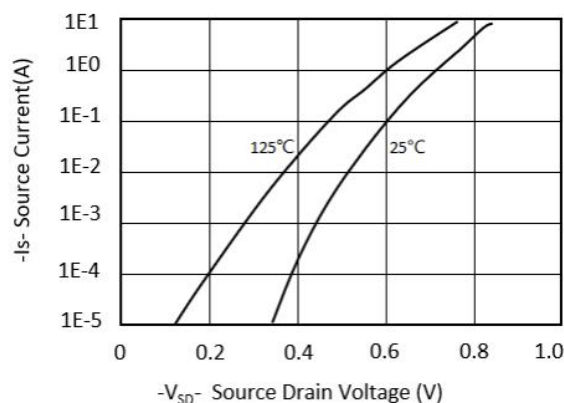


Figure 4. Body Diode Characteristics

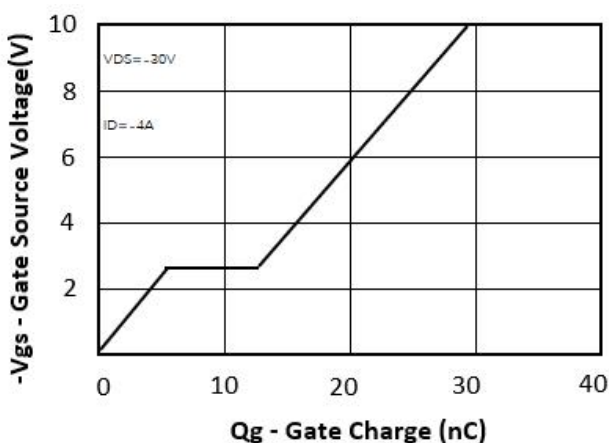


Figure 5. Gate Charge Characteristics

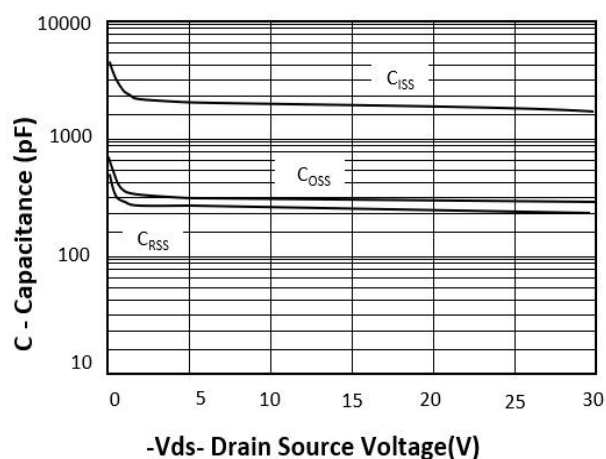


Figure 6. Capacitance Characteristics

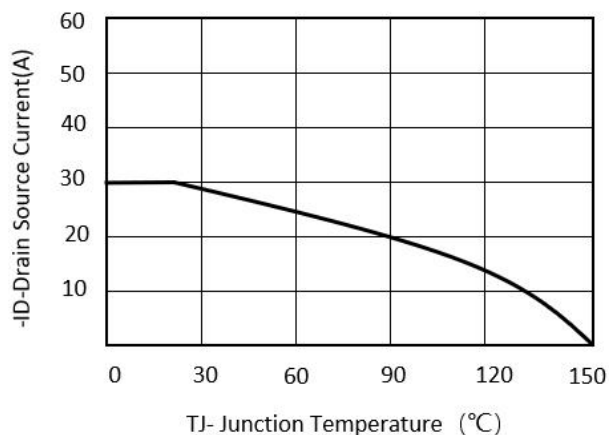


Figure 7. Current De-rating

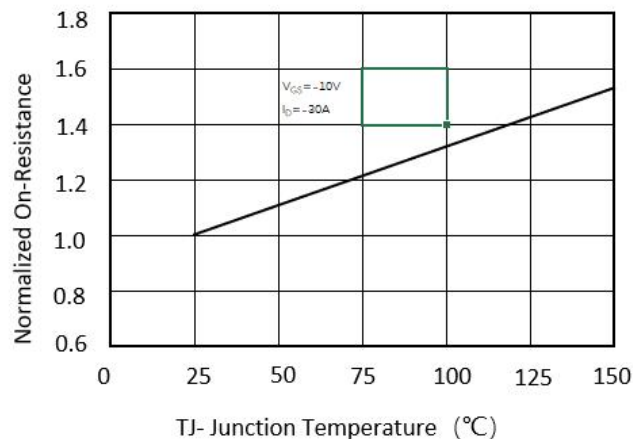


Figure 8. On-Resistance vs. Junction Temperature

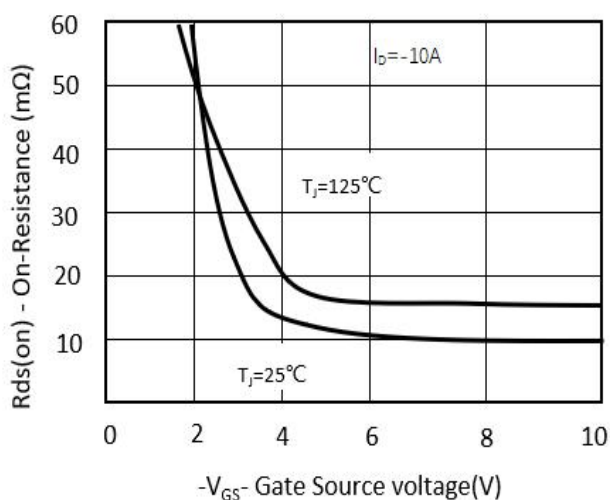


Figure 9. On-Resistance vs. Gate-Source Voltage

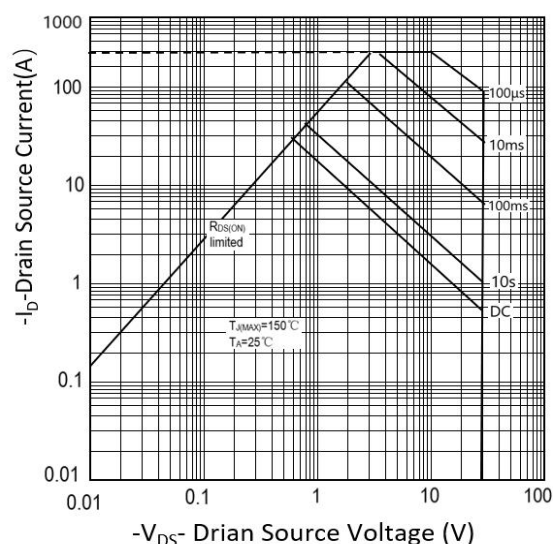


Figure 10. Safe Operation Area

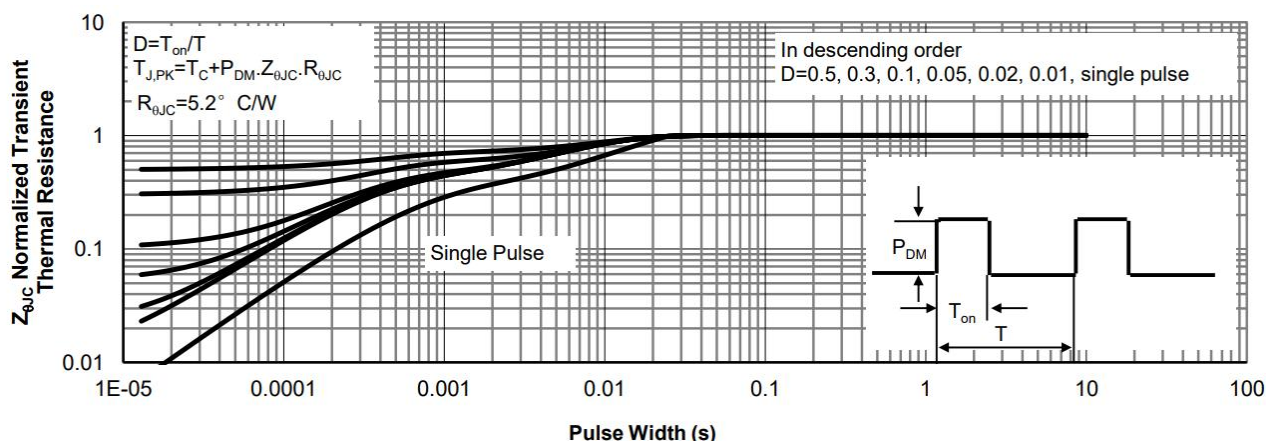


Figure 11. Normalized Maximum Transient Thermal Impedance

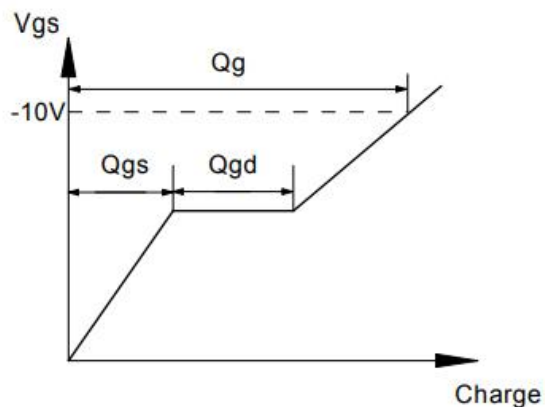
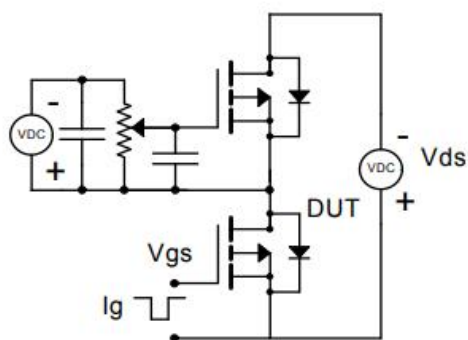


Figure 12. Gate Charge Test Circuit & Waveform

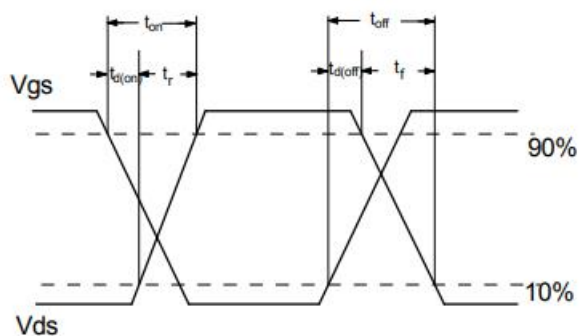
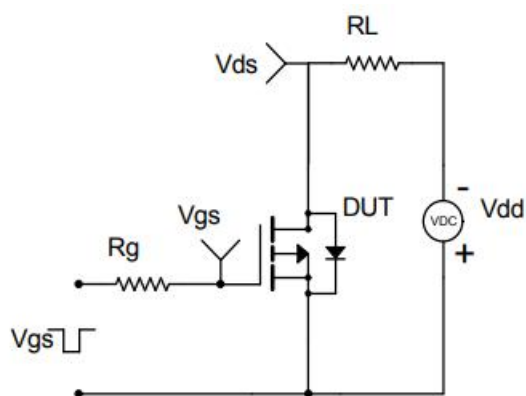


Figure 13. Resistive Switching Test Circuit & Waveforms

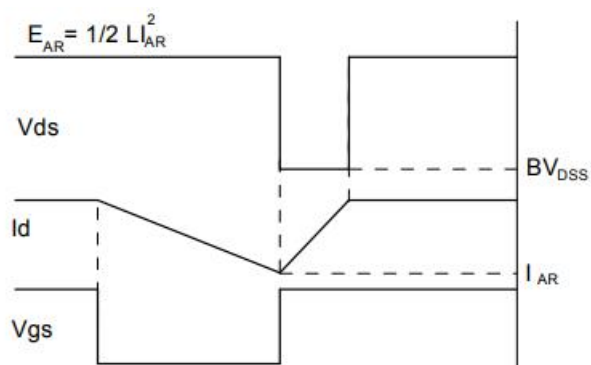
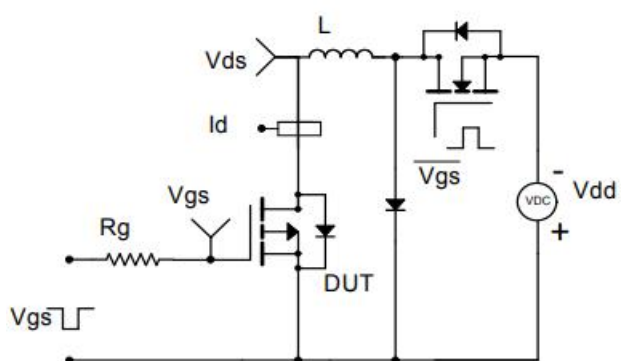


Figure 14. Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

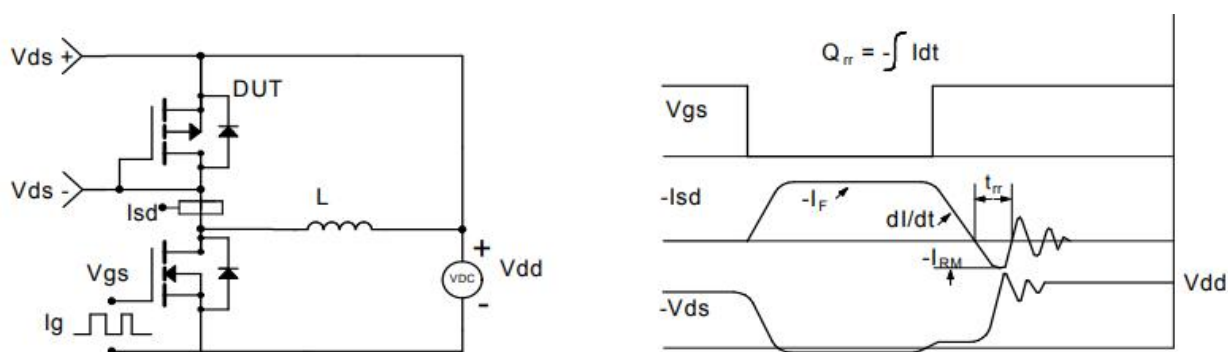
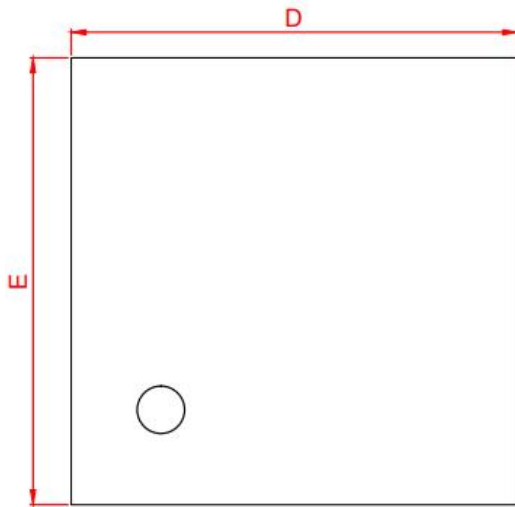
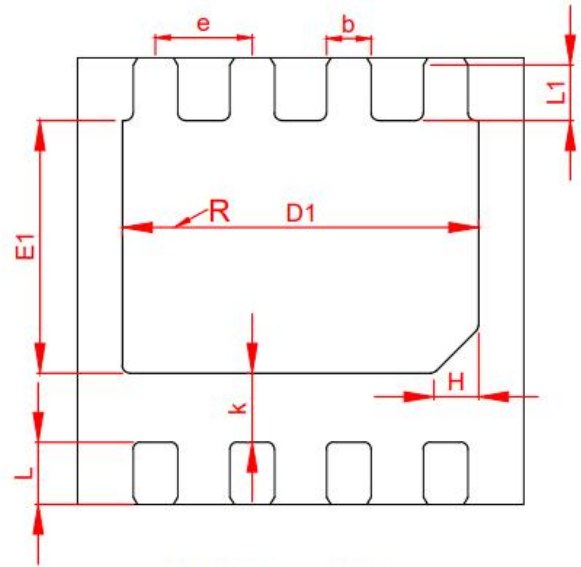


Figure 15. Diode Recovery Test Circuit & Waveforms

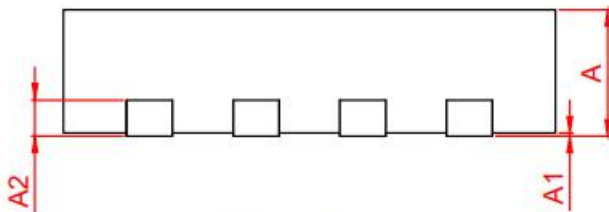
DFN3*3 Package Information



TOP VIEW



BOTTOM VIEW



SIDE VIEW

SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	0.70	0.75	0.80
* A1	0.00	0.02	0.05
* b	0.27	0.32	0.37
* A2	0.20REF		
* D	2.90	3.00	3.10
* E	2.90	3.00	3.10
* E1	1.70	1.80	1.90
* D1	2.35	2.45	2.55
* e	0.65BSC		
* L	0.35	0.40	0.45
h	0.30 REF		
* k	0.50REF		
* L1	0.25	0.30	0.35

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